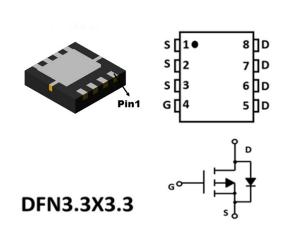
# P-Channel Enhancement Mode Field Effect Transistor



## **Product Summary**

- V<sub>DS</sub> • I<sub>D</sub>
- ID
  R<sub>DS(ON)</sub>( at V<sub>GS</sub>= -4.5V)
- -55A <8.3mohm

<10mohm

<15mohm

-20V

- R<sub>DS(ON)</sub>( at V<sub>GS</sub>= -2.5V)
- R<sub>DS(ON)</sub>( at V<sub>GS</sub>= -1.8V)
- 100% UIS Tested
- 100%  $\bigtriangledown$  V<sub>DS</sub> Tested

## **General Description**

- Trench Power LV MOSFET technology
- Excellent package for heat dissipation
- High density cell design for low R<sub>DS(ON)</sub>

## Applications

- High current load applications
- Load switching
- Hard switched and high frequency Circuits
- Uninterruptible power supply

## ■ Absolute Maximum Ratings (T<sub>A</sub>=25°Cunless otherwise noted)

Parameter		Symbol	Limit	Unit	
Drain-source Voltage		V <sub>DS</sub>	-20	V	
Gate-source Voltage		V <sub>GS</sub>	±10	V	
Drain Current	T <sub>A</sub> =25℃		55	A	
	T <sub>A</sub> =100°C	- I <sub>D</sub> -	35		
Pulsed Drain Current <sup>A</sup>		I <sub>DM</sub>	160	А	
Single Pulse Avalanche Energy <sup>B</sup>		E <sub>AS</sub>	75	mJ	
Total Power Dissipation	T <sub>c</sub> =25℃	• P <sub>D</sub>	38	W	
	T <sub>A</sub> =25℃	ΓD	3.2		
Thermal Resistance Junction-to-Case		Rejc	3.3	°C / <b>\\</b> /	
		R <sub>0JA</sub>	39	°C/ <b>W</b>	
Junction and Storage Temperature Range		T <sub>J</sub> ,T <sub>STG</sub>	-55~+150	°C	

## Ordering Information (Example)

PREFERED P/N	PACKING CODE	Marking	MINIMUM PACKAGE(pcs)	INNER BOX QUANTITY(pcs)	OUTER CARTON QUANTITY(pcs)	DELIVERY MODE
YJQ55P02A	F1	Q55P02A	5000	10000	100000	13" reel
4/7						



## YJQ55P02A

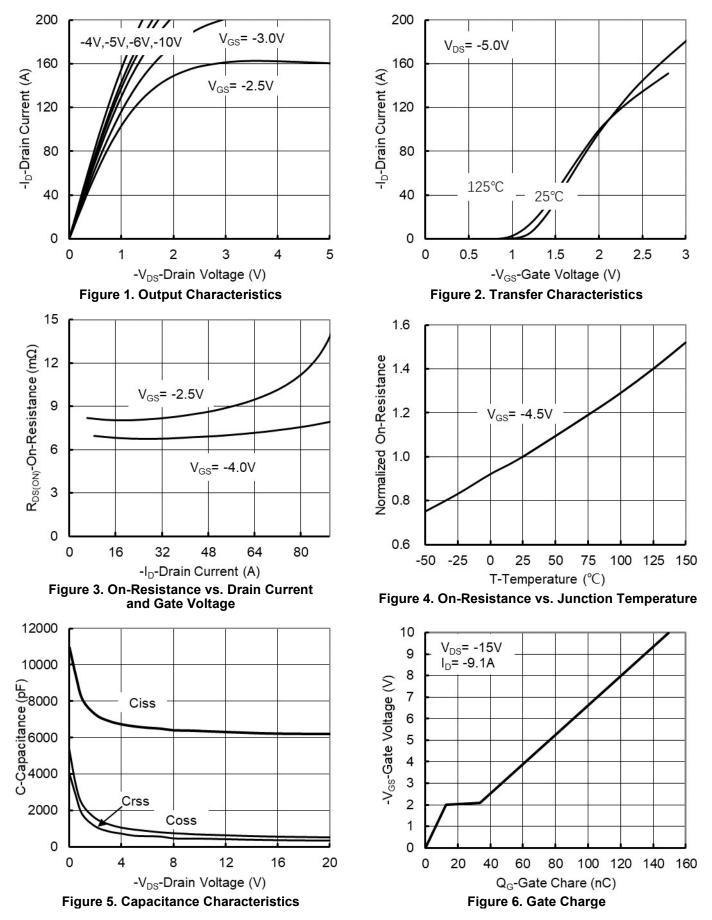
#### ■ Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)

Parameter	Symbol	Conditions	Min	Тур	Мах	Units	
Static Parameter							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	$V_{GS}$ = 0V, I <sub>D</sub> =250µA	-20			V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =-20V,V <sub>GS</sub> =0V			1	μA	
Gate-Body Leakage Current	I <sub>GSS</sub>	$V_{GS}\text{=}\pm10V,V_{DS}\text{=}0V$			±100	nA	
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}$ = $V_{GS}$ , $I_D$ =-250 $\mu$ A	-0.4	-0.62	-1.0	V	
		V <sub>GS</sub> = -4.5V, I <sub>D</sub> =-15A		6.5	8.3		
Static Drain-Source On-Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> = -2.5V, I <sub>D</sub> =-10A		8.0	10.0	mΩ	
		V <sub>GS</sub> = -1.8V, I <sub>D</sub> =-8.0A		10.3	15		
Diode Forward Voltage	V <sub>SD</sub>	I <sub>S</sub> =-20A,V <sub>GS</sub> =0V		-0.7	-1.2	V	
Maximum Body-Diode Continuous Current	Is				-55	А	
Dynamic Parameters							
Input Capacitance	C <sub>iss</sub>			6358		pF	
Output Capacitance	C <sub>oss</sub>	$V_{DS}$ =-10V, $V_{GS}$ =0V,f=1MHZ		690			
Reverse Transfer Capacitance	C <sub>rss</sub>			477			
Switching Parameters							
Total Gate Charge	Qg			12.7			
Gate-Source Charge	Q <sub>gs</sub>	V <sub>GS</sub> =-10V,V <sub>DS</sub> =-15V,I <sub>D</sub> =-9.1A		21		nC	
Gate-Drain Charge	Q <sub>gd</sub>			149			
Reverse Recovery Charge	Q <sub>rr</sub>			25.2			
Reverse Recovery Time	t <sub>rr</sub>	I <sub>F</sub> =-6A, di/dt=100A/us		46			
Turn-on Delay Time	t <sub>D(on)</sub>			11		ns	
Turn-on Rise Time	tr	V <sub>GS</sub> =-10V,V <sub>DD</sub> =-15V, I <sub>D</sub> =-6A		36			
Turn-off Delay Time	t <sub>D(off)</sub>	$R_{GEN}=2.5\Omega$		182			
Turn-off fall Time	t <sub>f</sub>			191			

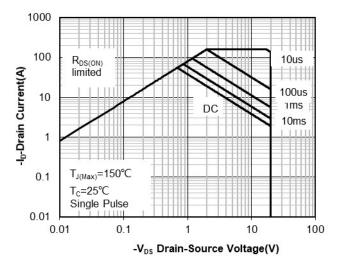
A. Pulse Test: Pulse Width  ${\leqslant}300 \text{us,Duty cycle} {\leqslant}2\%.$ 

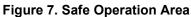
B.  $R_{\theta,JA}$  is the sum of the junction-to-case and case-to-ambient thermal resistance, where the case thermal reference is defined as the solder mounting surface of the drain pins.  $R_{\theta,JC}$  is guaranteed by design, while  $R_{\theta,JA}$  is determined by the board design. The maximum rating presented here is based on mounting on a 1 in 2 pad of 2oz copper.

## Typical Performance Characteristics



# YJQ55P02A





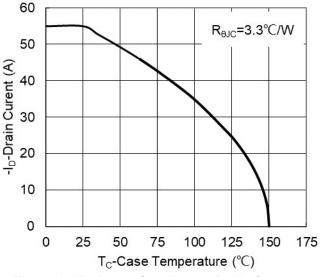


Figure 8. Maximum Continuous Drain Current vs Case Temperature

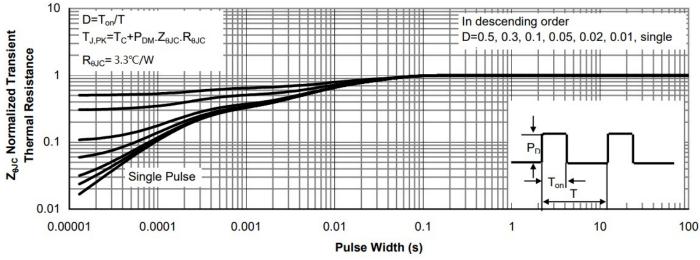
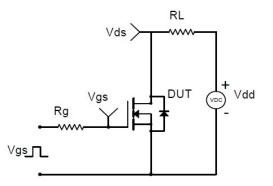
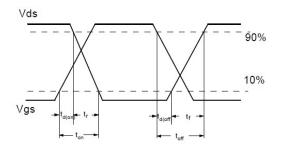


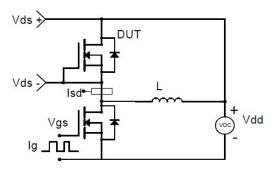
Figure 9. Normalized Maximum Transient Thermal Impedance

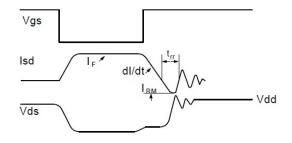
4/7



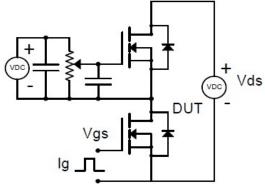


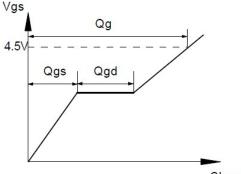
#### **Resistive Switching Test Circuit & Waveforms**





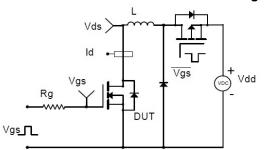
## **Diode Recovery Test Circuit & Waveforms**

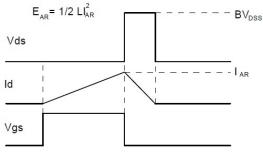




Charge

## Gate Charge Test Circuit & Waveform

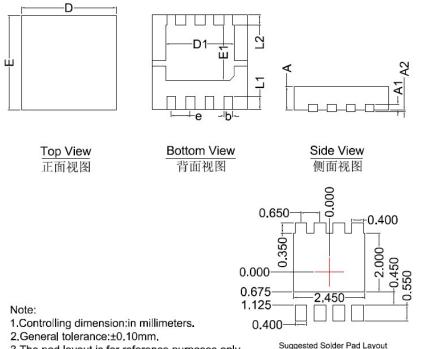




**Unclamped Inductive Switching (UIS) Test Circuit & Waveforms** 

5/7

## ■DFN3.3X3.3 Package information



SYMBOL	MILLIMETER				
	MIN	NOM	MAX		
D	3.15	3.25	3.35		
E	3.15	3.25	3.35		
A	0.70 0.80 0.9		0.90		
A1	0.20 BSC				
A2			0.10		
D1	2.20	2.35	2.50		
E1	1.80	1.90	2.00		
L1	0.35	0.35 0.45 0			
L2	0.35 BSC				
b	0.20	0.30	0.40		
е	0.65 BSC				

3. The pad layout is for reference purposes only.

Suggested Solder Pad Layout Top View

6/7



# YJQ55P02A

#### Disclaimer

The information presented in this document is for reference only. Yangzhou Yangjie Electronic Technology Co., Ltd. reserves the right to make changes without notice for the specification of the products displayed herein to improve reliability, function or design or otherwise.

The product listed herein is designed to be used with ordinary electronic equipment or devices, and not designed to be used with equipment or devices which require high level of reliability and the malfunction of with would directly endanger human life (such as medical instruments, transportation equipment, aerospace machinery, nuclear-reactor controllers, fuel controllers and other safety devices), Yangjie or anyone on its behalf, assumes no responsibility or liability for any damages resulting from such improper use of sale.

This publication supersedes & replaces all information previously supplied. For additional information, please visit our website http:// www.21yangjie.com, or consult your nearest Yangjie's sales office for further assistance.